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Thao P Le

2818

SEARCHED			
Class	Subclass	Date	Examiner
438	14	10/23/2003	T.LE

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST wafer cleaning, scan by laser	10/22/2003	T.LE
EAST	10/23/2003	T.Le